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With the principle of "Quality Parts,Customers Priority,Honest Operation,and Considerate Service",our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



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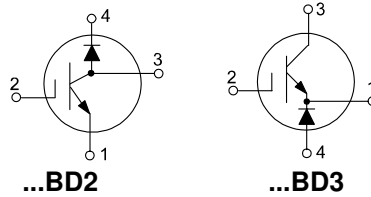


HiPerFAST™ IGBT with HiPerFRED

IXGN 50N60BD2 IXGN 50N60BD3

$V_{CES} = 600 \text{ V}$
 $I_{C25} = 75 \text{ A}$
 $V_{CE(sat)} = 2.5 \text{ V}$
 $t_{fi} = 150 \text{ ns}$

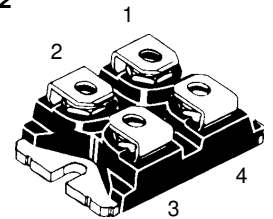
Buck & boost configurations



	Symbol	Test Conditions	Maximum Ratings	
IGBT	V_{CES}	$T_J = 25^\circ\text{C}$ to 150°C	600	V
	V_{CGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GE} = 1 \text{ M}\Omega$	600	V
	V_{GES}	Continuous	± 20	V
	V_{GEM}	Transient	± 30	V
	I_{C25}	$T_C = 25^\circ\text{C}$	75	A
	I_{C90}	$T_C = 90^\circ\text{C}$	50	A
	I_{CM}	$T_C = 25^\circ\text{C}$, 1 ms	200	A
	SSOA (RBSOA)	$V_{GE} = 15 \text{ V}$, $T_{VJ} = 125^\circ\text{C}$, $R_G = 10 \Omega$ Clamped inductive load, $L = 30 \mu\text{H}$	$I_{CM} = 100$ @ $0.8 V_{CES}$	A
	P_C	$T_C = 25^\circ\text{C}$	250	W
	Diode	V_{RRM}		600
I_{FAVM}		$T_C = 70^\circ\text{C}$; rectangular, $d = 50\%$	60	A
I_{FRM}		$t_p < 10 \text{ ms}$; pulse width limited by T_J	600	A
P_D		$T_C = 25^\circ\text{C}$	150	W
Case	T_J		-40 ... +150	$^\circ\text{C}$
	T_{JM}		150	$^\circ\text{C}$
	T_{stg}		-40 ... +150	$^\circ\text{C}$
	M_d	Mounting torque Terminal connection torque (M4)	1.5/13 1.5/13	Nm/lb.in.
	Weight		30	g
	Maximum lead temperature for soldering 1.6 mm (0.062 in.) from case for 10 s		300	$^\circ\text{C}$

SOT-227B, miniBLOC

E 153432



IXGN50N60BD2

1 = Emitter; 2 = Gate
3 = Collector; 4 = Diode cathode

IXGN50N60BD3

1 = Emitter/Diode Cathode; 2 = Gate
3 = Collector; 4 = Diode anode

Features

- International standard package miniBLOC
- Aluminium nitride isolation
 - high power dissipation
- Isolation voltage 3000 V~
- Very high current, fast switching IGBT & FRED diode
- MOS Gate turn-on
 - drive simplicity
- Low collector-to-case capacitance
- Low package inductance (< 10 nH)
 - easy to drive and to protect
- Molding epoxies meet UL94 V-0 flammability classification

Applications

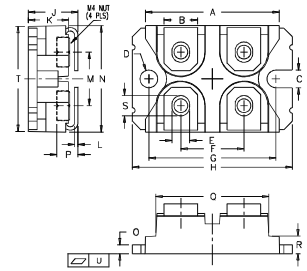
- AC motor speed control
- DC servo and robot drives
- DC choppers
- Buck converters

Advantages

- Easy to mount with 2 screws
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)		
		min.	typ.	max.
BV_{CES}	$I_C = 250 \mu\text{A}$, $V_{GE} = 0 \text{ V}$	600		V
$V_{GE(th)}$	$I_C = 250 \mu\text{A}$, $V_{CE} = V_{GE}$	2.5		5 V
I_{CES}	$V_{CE} = 0.8 \cdot V_{CES}$ $V_{GE} = 0 \text{ V}$			200 μA 1 mA
I_{GES}	$V_{CE} = 0 \text{ V}$, $V_{GE} = \pm 20 \text{ V}$			$\pm 100 \text{ nA}$
$V_{CE(sat)}$	$I_C = I_{C90}$, $V_{GE} = 15 \text{ V}$			2.5 V

Symbol	Test Conditions	Characteristic Values ($T_J = 25^\circ\text{C}$, unless otherwise specified)			
		min.	typ.	max.	
g_{fs}	$I_C = I_{C90}$; $V_{CE} = 10\text{ V}$, Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$	35	50	S	
C_{ies}	$V_{CE} = 25\text{ V}$, $V_{GE} = 0\text{ V}$, $f = 1\text{ MHz}$		4100	pF	
C_{oes}			290	pF	
C_{res}			50	pF	
Q_g	$I_C = I_{C90}$, $V_{GE} = 15\text{ V}$, $V_{CE} = 0.5 V_{CES}$		110	nC	
Q_{ge}			30	nC	
Q_{gc}			35	nC	
$t_{d(on)}$	Inductive load, $T_J = 25^\circ\text{C}$ $I_C = I_{C90}$, $V_{GE} = 15\text{ V}$, $L = 100\ \mu\text{H}$, $V_{CE} = 0.8 V_{CES}$, $R_G = R_{off} = 2.7\ \Omega$ Remarks: Switching times may increase for V_{CE} (Clamp) $> 0.8 \cdot V_{CES}$, higher T_J or increased R_G		50	ns	
t_{ri}			50	ns	
$t_{d(off)}$			110	250	ns
t_{fi}			150	220	ns
E_{off}			3.0	4.0	mJ
R_{thJC}					0.50
R_{thCK}		0.05		K/W	

miniBLOC, SOT-227 B


M4 screws (4x) supplied

Dim.	Millimeter		Inches	
	Min.	Max.	Min.	Max.
A	31.50	31.88	1.240	1.255
B	7.80	8.20	0.307	0.323
C	4.09	4.29	0.161	0.169
D	4.09	4.29	0.161	0.169
E	4.09	4.29	0.161	0.169
F	14.91	15.11	0.587	0.595
G	30.12	30.30	1.186	1.193
H	38.00	38.23	1.496	1.505
J	11.68	12.22	0.460	0.481
K	8.92	9.60	0.351	0.378
L	0.76	0.84	0.030	0.033
M	12.60	12.85	0.496	0.506
N	25.15	25.42	0.990	1.001
O	1.98	2.13	0.078	0.084
P	4.95	5.97	0.195	0.235
Q	26.54	26.90	1.045	1.059
R	3.94	4.42	0.155	0.174
S	4.72	4.85	0.186	0.191
T	24.59	25.07	0.968	0.987
U	-0.05	0.1	-0.002	0.004

Reverse Diode (FRED)
Characteristic Values

 ($T_J = 25^\circ\text{C}$, unless otherwise specified)

Symbol	Test Conditions	typ.	max.
I_R	$T_{VJ} = 25^\circ\text{C}$ $V_R = V_{RRM}$ $T_{VJ} = 150^\circ\text{C}$		650 μA 2.5 mA
V_F	$I_F = 60\text{ A}$, $T_{VJ} = 150^\circ\text{C}$ Pulse test, $t \leq 300\ \mu\text{s}$, duty cycle $d \leq 2\%$ $T_{VJ} = 25^\circ\text{C}$		1.75 V 2.40 V
I_{RM}	$I_F = I_{C90}$, $V_{GE} = 0\text{ V}$, $-di_F/dt = 100\text{ A}/\mu\text{s}$ $V_R = 540\text{ V}$		8.0 A
t_{rr}	$I_F = 1\text{ A}$, $-di_F/dt = 50\text{ A}/\mu\text{s}$, $V_R = 30\text{ V}$ $T_J = 25^\circ\text{C}$	35	ns
R_{thJC}			0.85 K/W

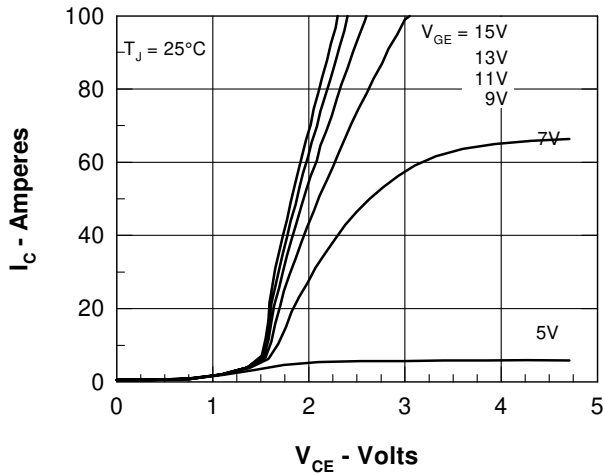


Fig. 1. Saturation Voltage Characteristics

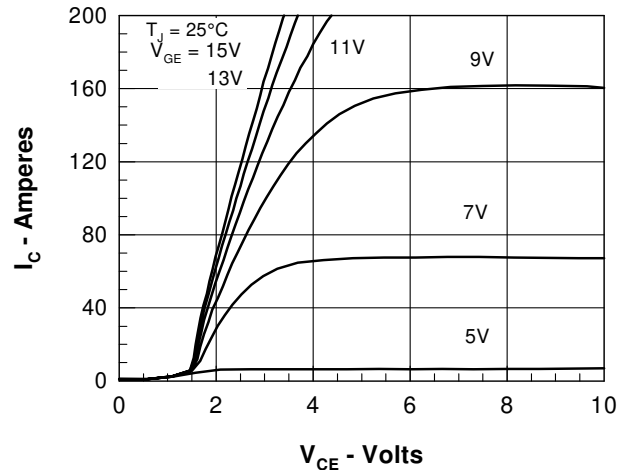


Fig. 2. Extended Output Characteristics

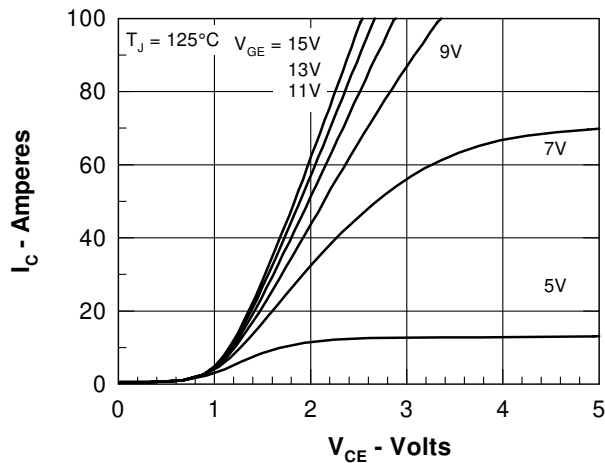


Fig. 3. Saturation Voltage Characteristics

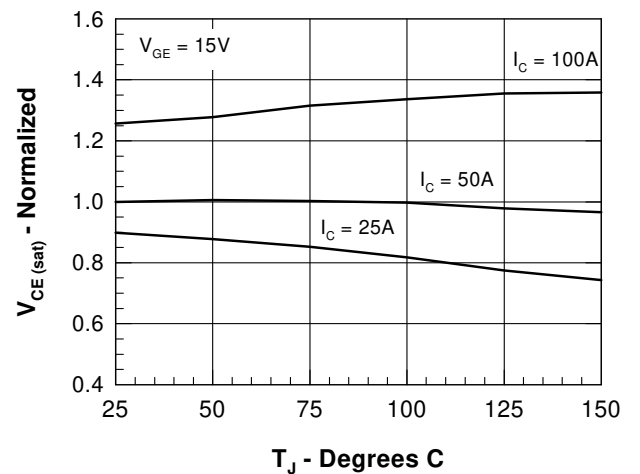


Fig. 4. Temperature Dependence of $V_{CE(sat)}$

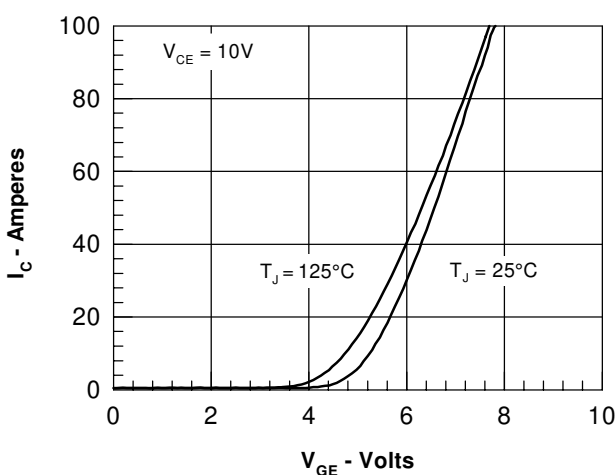


Fig. 5. Saturation Voltage Characteristics

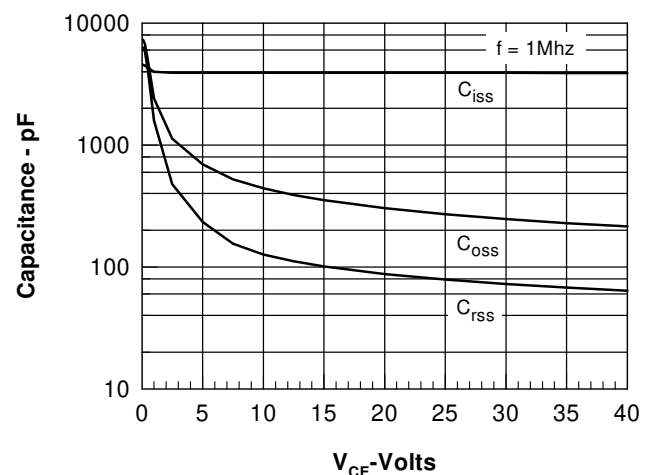


Fig. 6. Junction Capacitance Curves

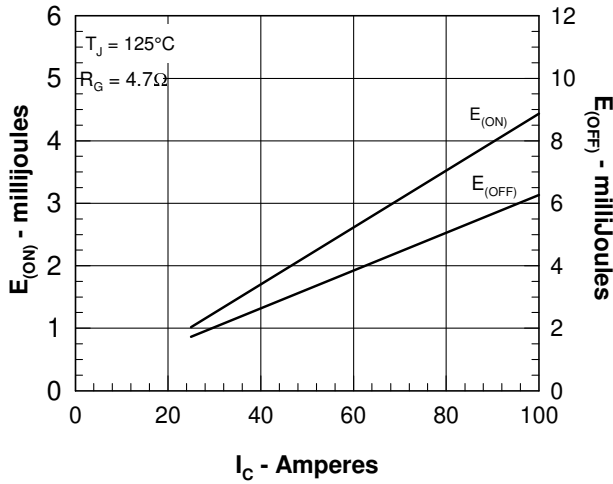


Fig. 7. Dependence of E_{ON} and E_{OFF} on I_C .

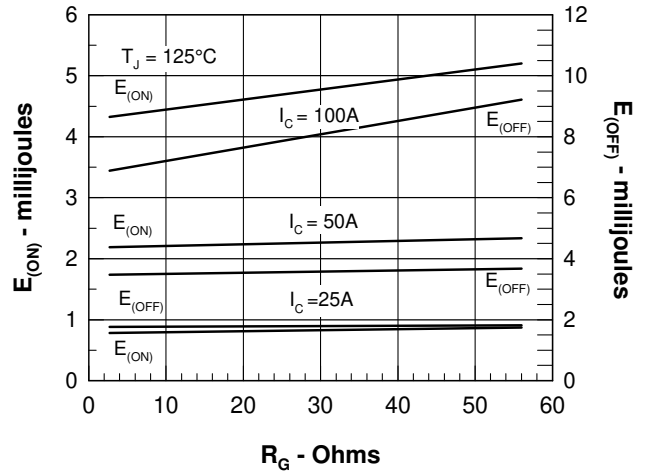


Fig. 8. Dependence of t_{fi} and E_{OFF} on R_G .

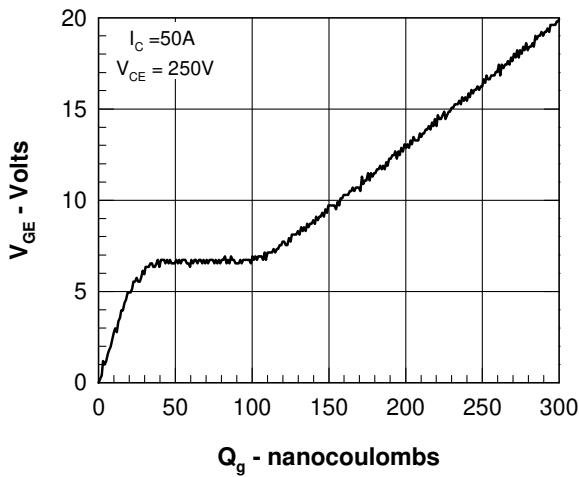


Fig. 9. Gate Charge

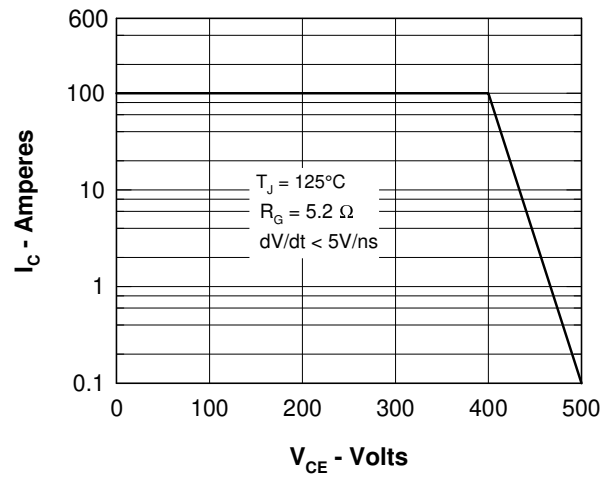


Fig. 10. Turn-off Safe Operating Area

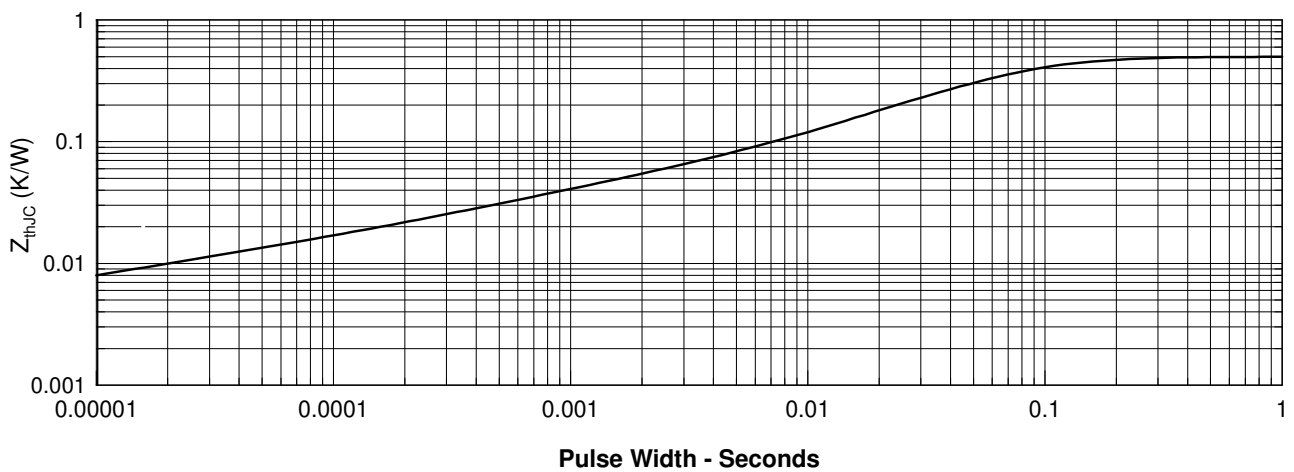


Fig. 11. Transient Thermal Resistance

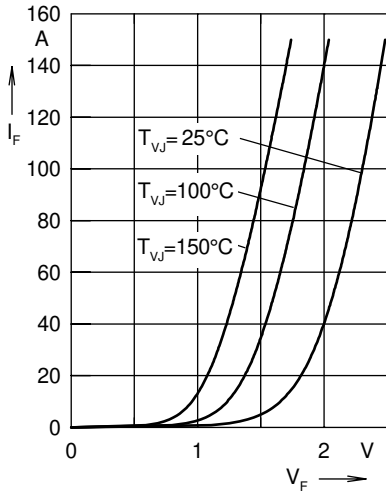


Fig. 12 Forward current I_F versus V_F

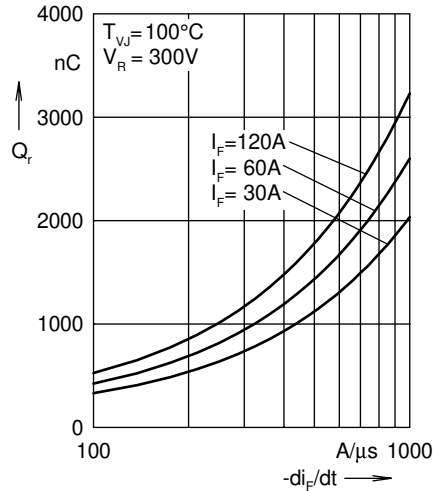


Fig. 13 Reverse recovery charge Q_r versus $-di_F/dt$

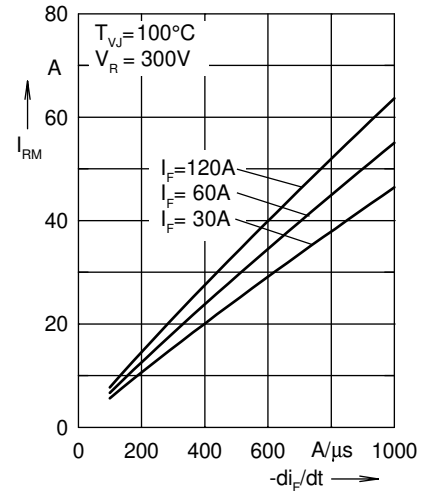


Fig. 14 Peak reverse current I_{RM} versus $-di_F/dt$

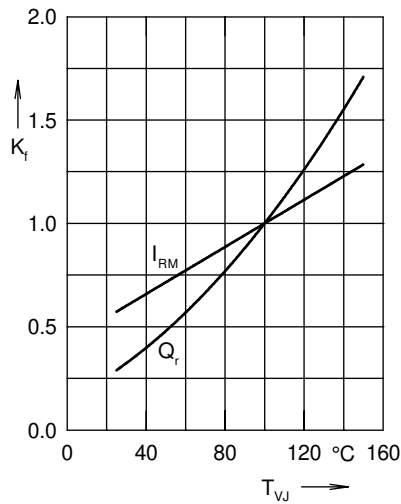


Fig. 15 Dynamic parameters Q_r , I_{RM} versus T_{VJ}

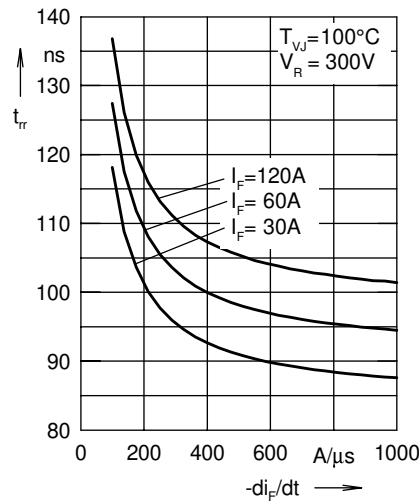


Fig. 16 Recovery time t_{rr} versus $-di_F/dt$

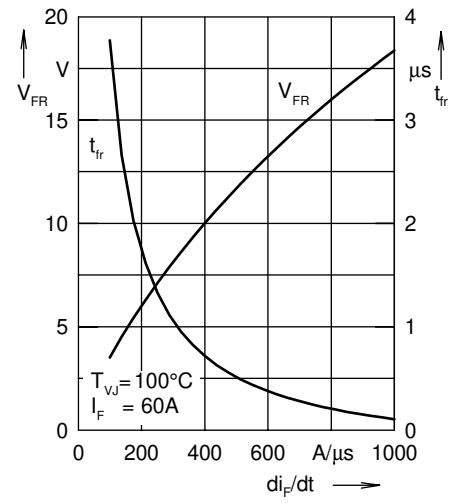


Fig. 17 Peak forward voltage V_{FR} and t_{fr} versus di_F/dt

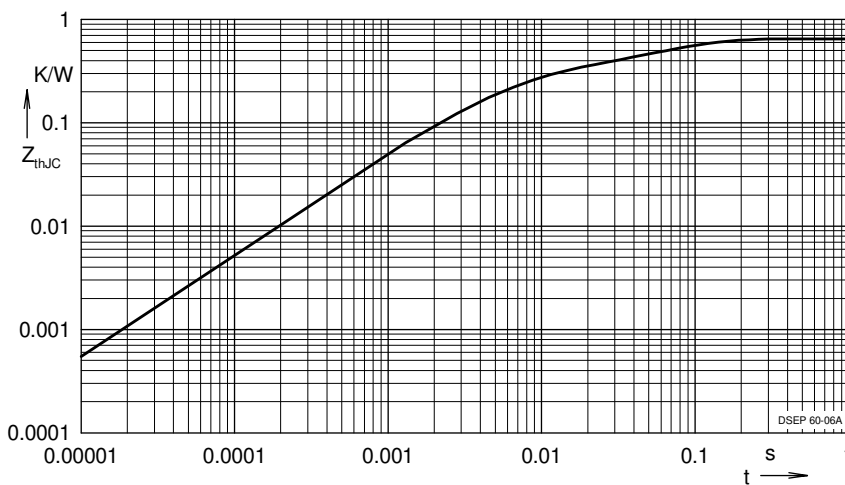


Fig. 18 Transient thermal resistance junction to case

Constants for Z_{thJC} calculation:

i	R_{thi} (K/W)	t_i (s)
1	0.324	0.0052
2	0.125	0.0003
3	0.201	0.0385